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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/725,795
Applicant : Chieh Ou-Yanget
iling Date : December 2, 2003
Title: : "METHOD AND APPARATUS FOR CONTROL OF LAYER THICKNESSES"

TC/AU : 1765

Docket No. : 35194US1
Customer No. : 00116

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir/Madam:

In accordance with Rule 56, applicant is aware of the publications listed in the International Search Report (copy enclosed) and in the enclosed copy of Patent Office Form 1449.

In accordance with the notification issued by the Office of Patent Legal Administration dated June 17, 2003, the requirement to submit the cited U.S. references is waived as the above-referenced application was filed after June 30, 2003. The two cited non-U.S. references are enclosed.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date indicated below.

Michael W. Garvey
Name of Attorney for Applicant(s)
8 APR 05 Date
Signature of Attorney

If there are any further fees resulting from this communication not covered by the enclosed check, or if no check was enclosed, please charge the same to Deposit Account No. 16-0820, Order No. 35194US1.

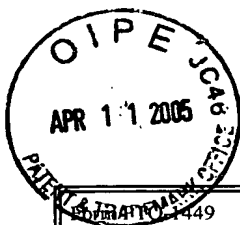
Respectfully submitted,
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By _____

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INFORMATION DISCLOSURE CITATION BY APPLICANT	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 35194US1	SERIAL NO. 10/725,795
	APPLICANT: cHIEH oU-yANG			
	FILING DATE: December 2, 2003		GROUP ART UNIT: 1765	

U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Date	Name	Class	Subclass	Filing Date if Appropriate
	A	2002/011478 A1	1/2002	Ratliff			
	B	6,174,651 B1	1/2001	Thakur			
	C	5,487,127	1/1996	Gibbons			
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FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Class	Subclass	Translation
	L	99/16019 A	4/1999	WO			cited in ISR
	M	0 840 357 A	5/1998	EP			cited in ISR
	N						
	Q						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	R	
	S	
	T	

Examiner:	Date Considered
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*Examiner: Initial if reference considered, regardless of whether citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.